Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/049,522	HEYMANN ET AL.	
Examiner	Art Unit	
Ajay M. Bhatia	2145	

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	203 204 206 207 217 218 219	6/7/2005	АВ
709	226 248	6/7/2005	AB
715	513 760	6/7/2005	АВ
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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6/10/2005 - 6/7/2005	AB AB
6/7/2005	АВ
6/9/2005	АВ